

An IATF 16949, ISO9001 and ISO 14001 Certified Company





PNP SILICON EPITAXIAL TRANSISTORS



Pin Configuration

1 = BASE

2 = EMITTER

3 = COLLECTOR

CMBT3906

SOT-23 Surface Mount Plastic Package RoHS compliant

APPLICATIONS:

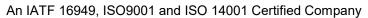
SOT-23

This device is designed for general-purpose amplifier and switching applications.

ABSOLUTE MAXIMUM RATINGS ($T_a = 25$ °C)

Parameter	SYMBOL	VALUE	UNIT	
Collector–base voltage (open emitter)	-V _{CB0}	40	V	
Collector–emitter voltage (open base)	-V _{CE0}	40	V	
Emitter–base voltage (open collector)	-V _{EB0}	5	V	
Collector current (d.c.)	-I _C	200	mA	
Total power dissipation up to Tamb = 25 °C P _{tot}		250	mW	
D.C. current gain at $-I_C = 10$ mA; $-V_{CE} = 1$ V	h _{FE}	100 to 300		
Transition frequency at f = 100 MHz $-I_C = 10$ mA; $-V_{CE} = 20$ V	f _T	250	MHz	
Storage temperature	T _{stg}	-55 to +150	°C	
THERMAL CHARACTERISTICS				
$Tj = P(R_{\theta j-t} + R_{\theta t-s} + R_{\theta s-a}) + T_{amb}$ Thermal resistance from junction to ambient	$R_{\scriptscriptstyle{\theta(j\text{-}a)}}$	500	K/W	





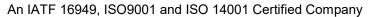




ELECTRICAL CHARACTERISTICS at T_a = 25 °C

Power of or		ndition Symbol	Value			Unit
Parameter	Test Condition		Min	Тур.	Max	Unit
Collector–emitter breakdown voltage	$-I_{C} = 1mA; I_{B} = 0$	$-V_{(BR)CE0}$	40			V
Collector–base breakdown voltage	$-I_C = 10\mu A; I_E = 0$	-V _{(BR)CB0}	40	1		V
Emitter–base breakdown voltage	$-I_E = 10 \mu A; I_C = 0$	$-V_{(BR)EB0}$	5	1		V
Collector cut-off current	$-V_{CE}$ =30V; $-V_{EB}$ =3 V	-I _{CEX}		-	50	nA
Base current with reverse biased emitter		-I _{BEX}			50	nA
Output capacitance at f =100 kHz	$I_E = 0; -V_{CB} = 5V$	C _c			4.5	pF
Input capacitance at f=100 kHz	$I_C = 0$; $-V_{BE} = 0.5V$	C _e			10	pF
	$-I_{C} = 10 \text{mA}; -I_{B} = 1 \text{ mA}$	-V _{CEsat}			0.25	V
Saturation voltages	$-I_{C} = 50 \text{mA}; -I_{B} = 5 \text{mA}$	$-V_{\sf CEsat}$			0.4	V
Saturation voltages	$-I_{C} = 10mA; -I_{B} = 1mA$	–V _{BEsat}	0.65		0.85	V
	$-I_{C} = 50 \text{mA}; -I_{B} = 5 \text{mA}$	–V _{BEsat}			0.95	V
	$-I_C = 0.1 \text{mA}; -V_{CE} = 1V$	h _{FE}	60			
	$-I_{C} = 1mA; -V_{CE} = 1V$	h _{FE}	80			
D.C. current gain	$-I_C = 10mA; -V_{CE} = 1V$	h _{FE}	100		300	
	$-I_C = 50 \text{mA}; -V_{CE} = 1 \text{V}$	h _{FE}	60			
	-I _C =100mA;-V _{CE} =1V	h _{FE}	30	-		
Transition frequency at f = 100 MHz	$-I_C = 10$ mA; $-V_{CE} = 20$ V	f _T	250		-	MHz
Noise figure at RS = 1 kΩ	$-I_C = 100\mu A; -V_{CE} = 5 V,$	F			4	Db
	f = 10 Hz to 15,7 kHz	ı				טט
Small Signal Current Gain	$V_{CE} = 10V; I_{C} = 1 \text{ mA};$	h _{fe}	100		400	
SWITCHING Time CHARACTERIS	STICS					
Delay time	V_{CC} =3V, V_{BE} =0.5V	t_d	< 35		< 35	ns
Rise time	I _C =10mA, I _B 1=1mA	t _r	< 35		< 35	ns
Storage time	V _{CC} =3V, I _C =10mA	t _s	< 200		< 225	ns
Fall time	I _{B1} =1 _{B2} =1mA	t _f	< 60		< 75	ns









Typical Characteristic Curves

Figure 1. Delay and Rise Time Equivalent Test Circuit

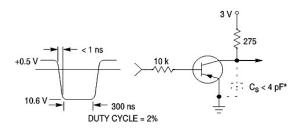
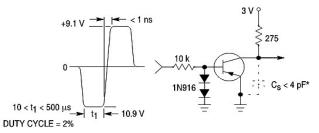


Figure 2. Storage and Fall Time Equivalent Test Circuit



* Total shunt capacitance of test jig and connectors

Figure 3. Capacitance

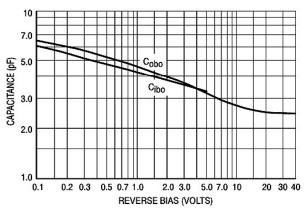


Figure 4. Charge Data

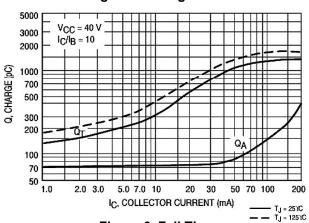


Figure 5. Turn-On Time

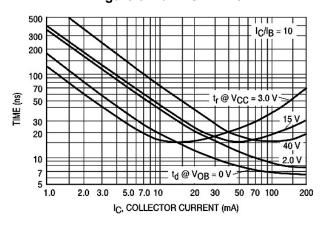
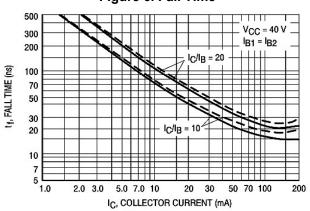
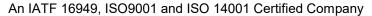


Figure 6. Fall Time











Typical Characteristic Curves

Figure 7. DC Current Gain

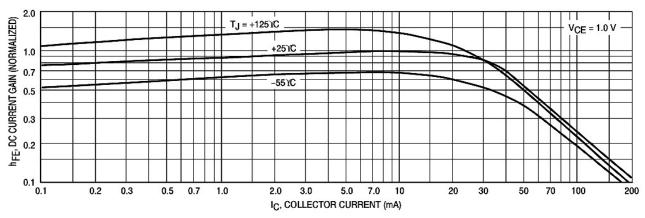


Figure 8. Collector Saturation Region

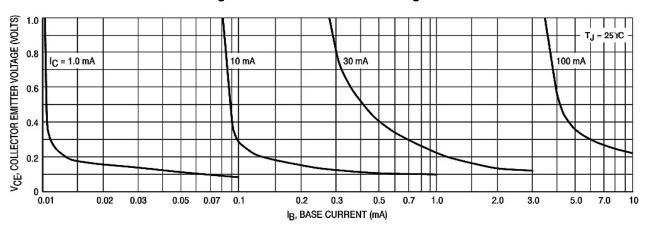


Figure 9. "ON" Voltages

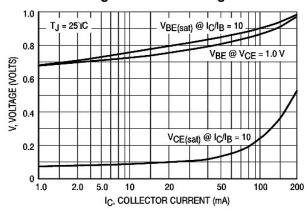
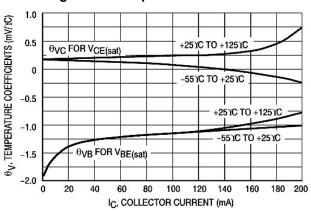
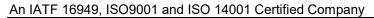


Figure 10. Temperature Coefficients



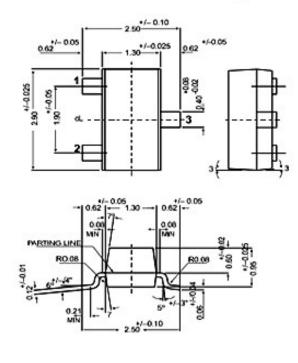




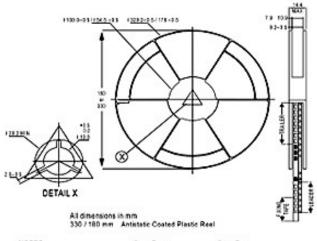


PACKAGE DETAILS

SOT-23 Formed SMD Package



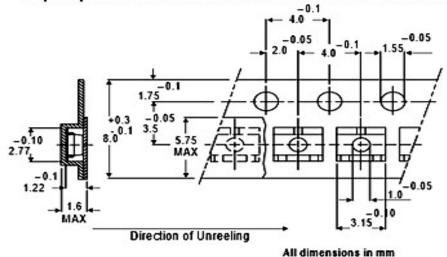
SOT-23 Package Reel Information Reel specifications for Packing (13"/7" reels)



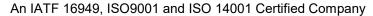
NOTES: 8mm Tape 8mm Tape 9 8mm Tape 100 8mm Tape 100

- 1. The bandoller of 330 mm reel contains at least 10,000 devices.
- 2. The bandoller of 180 mm reel contains at least 3,000 devices.
- No more than 0.5% missing devices / reel, 50 empty compartments for 330 mm reel.
 6 empty compartments for 180 mm reel.
- Three consecutive empty places might be found provided this gap is followed by 6 consecutive devices.
- The carrier tape (leader) starts with at least 75 empty positions (equivalent to 330 mm). In order to fix the carrier tape a self adhesive tape of 20 to 50 mm is applied. At the end of the bandoller at least 40 empty positions (equivalent to 160 mm) are there.

Tape Specification for SOT-23 Surface Mount Device











Recommended Product Storage Environment for Discrete Semiconductor Devices

This storage environment assumes that the Diodes and transistors are packed properly inside the original packing supplied by CDIL.

- · Temperature 5 °C to 30 °C
- · Humidity between 40 to 70 %RH
- · Air should be clean.
- · Avoid harmful gas or dust.
- · Avoid outdoor exposure or storage in areas subject to rain or water spraying.
- · Avoid storage in areas subject to corrosive gas or dust. Product shall not be stored in areas exposed to direct sunlight.
- · Avoid rapid change of temperature.
- · Avoid condensation.
- · Mechanical stress such as vibration and impact shall be avoided.
- · The product shall not be placed directly on the floor.
- The product shall be stored on a plane area. They should not be turned upside down. They should not be placed against the wall.

Shelf Life of CDIL Products

The shelf life of products is the period from product manufacture to shipment to customers. The product can be unconditionally shipped within this period. The period is defined as 2 years.

If products are stored longer than the shelf life of 2 years the products shall be subjected to quality check as per CDIL quality procedure.

The products are further warranted for another one year after the date of shipment subject to the above conditions in CDIL original packing.

Floor Life of CDIL Products and MSL Level

When the products are opened from the original packing, the floor life will start.

For this, the following JEDEC table may be referred:

JEDEC MSL Level				
Level	Time	Condition		
1	Unlimited	≤30 °C / 85% RH		
2	1 Year	≤30 °C / 60% RH		
2a	4 Weeks	≤30 °C / 60% RH		
3	168 Hours	≤30 °C / 60% RH		
4	72 Hours	≤30 °C / 60% RH		
5	48 Hours	≤30 °C / 60% RH		
5a	24 Hours	≤30 °C / 60% RH		
6	Time on Label(TOL)	≤30 °C / 60% RH		



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Customer Notes

Component Disposal Instructions

- 1. CDIL Semiconductor Devices are RoHS compliant, customers are requested to please dispose as per prevailing Environmental Legislation of their Country.
- 2. In Europe, please dispose as per EU Directive 2002/96/EC on Waste Electrical and Electronic Equipment (WEEE).

Disclaimer

The product information and the selection guides facilitate selection of the CDIL's Semiconductor Device(s) best suited for application in your product(s) as per your requirement. It is recommended that you completely review our Data Sheet(s) so as to confirm that the Device(s) meet functionality parameters for your application. The information furnished in the Data Sheet and on the CDIL Web Site/CD are believed to be accurate and reliable. CDIL however, does not assume responsibility for inaccuracies or incomplete information. Furthermore, CDIL does not assume liability whatsoever, arising out of the application or use of any CDIL product; neither does it convey any license under its patent rights nor rights of others. These products are not designed for use in life saving/support appliances or systems. CDIL customers selling these products (either as individual Semiconductor Devices or incorporated in their end products), in any life saving/support appliances or systems or applications do so at their own risk and CDIL will not be responsible for any damages resulting from such sale(s).

CDIL strives for continuous improvement and reserves the right to change the specifications of its products without prior notice.



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